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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/644,358	08/20/2003	Banqiu Wu	67493/52	6411	
1912 7	7590 09/09/2005		EXAMINER		
AMSTER, RO	OTHSTEIN & EBEN	AHMED, SHAMIM			
NEW YORK, NY 10016			ART UNIT	PAPER NUMBER	
			1765		

DATE MAILED: 09/09/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

				H 1	
		Application No.	Applicant(s)		
Office Action Summary		10/644,358	WU ET AL.		
		Examiner	Art Unit		
		Shamim Ahmed	1765		
Period fo	The MAILING DATE of this communication app or Reply	ears on the cover sheet with the c	orrespondence addi	ress	
WHIC - Exter after - If NO - Failu Any r	ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING DANSIONS of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. period for reply is specified above, the maximum statutory period we are to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing ed patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim vill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONEI). lety filed the mailing date of this com (35 U.S.C. § 133).		
Status					
2a) <u></u>	Responsive to communication(s) filed on <u>20 Au</u> This action is FINAL . 2b) This Since this application is in condition for allowant closed in accordance with the practice under E	action is non-final. nce except for formal matters, pro		merits is	
Dispositi	ion of Claims				
5)□ 6)⊠ 7)□	Claim(s) 1-93 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw Claim(s) is/are allowed. Claim(s) 1-93 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or	vn from consideration.			
Applicati	ion Papers				
10)⊠	The specification is objected to by the Examine The drawing(s) filed on 20 August 2003 is/are: Applicant may not request that any objection to the correction of the correctio	a) accepted or b) objected to drawing(s) be held in abeyance. See ion is required if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 CFF	R 1.121(d).	
Priority u	ınder 35 U.S.C. § 119				
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
2) Notic 3) Inform	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) r No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:	ite	152)	

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DETAILED ACTION

Information Disclosure Statement

1. The information disclosure statement filed 9/12/03 is merely duplicate version of the information disclosure statement (IDS) filed on 8/20/03. Accordingly, one of the versions of the IDS is crossed out.

Drawings

2. Figures 1A-1C, 2, 3A-3C and 4 should be designated by a legend such as --Prior Art-- because only that which is old is illustrated. See MPEP § 608.02(g). Corrected drawings in compliance with 37 CFR 1.121(d) are required in reply to the Office action to avoid abandonment of the application. The replacement sheet(s) should be labeled "Replacement Sheet" in the page header (as per 37 CFR 1.84(c)) so as not to obstruct any portion of the drawing figures. If the changes are not accepted by the examiner, the applicant will be notified and informed of any required corrective action in the next Office action. The objection to the drawings will not be held in abeyance.

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein

were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

5. Claims 1-93 are rejected under 35 U.S.C. 103(a) as being unpatentable over Applicants admitted prior art (AAPA, herein after) in view of Patrick et al (5,407,524).

AAPA discloses a process for making photomask utilizing a plasma etching process including the steps of:

- > providing a typical binary photomask blank comprising a photosensitive resist on the top of the blank photomask (paragraph 0003 at page 2);
- exposing the photosensitive resist layer for creating exposed (soluble) and unexposed (insoluble) portion and removing the soluble portion in order to expose an underlying layer (paragraph 0004);
- performing a dry etching may include plasma-assisted etch such as reactive ion etching (RIE) on the underlying layer (paragraph 0005).

AAPA fails to teach defining an endpoint and controlling the plasma etching process by monitoring at least one of parameters, wherein the parameter could comprises an automatic matching network parameter of the plasma etching process.

However, Patrick et al disclose an endpoint detection in plasma etching process by monitoring at least one plasma processing parameters such as components of an Application/Control Number: 10/644,358

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automatic matching network which is simple, cost effective ad reliable (col.3, lines 3-17 and also see col.5).

Patrick et al also disclose that one of the parameter such as in put voltage can be amplified to a desired value depending on the detected change in the matching network and needs to be adjusted (col.5, lines 10-28).

Patrick et al further teach that controlling the etching process with the use of a microprocessor that represents detection of the endpoint of the process (col.5, lines 60-col.6, lines 1-18).

Therefore, it would have been obvious to one of ordinary skilled in the art at the time of claimed invention to employ Patrick et al's teaching into AAPA's process for efficiently detecting the plasma etching process, which is simple, cost effective and reliable as taught by Patrick et al.

As to claims 9-14,41-46 and 71-76, Patrick et al teach that controlling the process by using a microprocessor, which includes a programmable data obviously having algorithm (col.5, lines 61-68).

As to claims 29,31,61 and 90, AAPA teaches that typically the underlying layer is chromium (paragraph 0003).

As to claims 28,30,60, 62, 89 and 91, AAPA teaches commonly binary and phase shift photomasks are used in the semiconductor industries (see the paragraph 0002).

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As to claims 15-16,47-50 and 77-80, AAPA teaches a radio frequency (RF) plasma and inductively coupled plasma (ICP) both are typically used in the plasma etching industries (see paragraphs 006-007).

Conclusion

6. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Desilets et al (4,362,596) teach an end point detection process in a plasma etching process by monitoring process parameter such as flow rate of the gaseous components (see abstract).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Shamim Ahmed whose telephone number is (571) 272-1457. The examiner can normally be reached on M-Thu (7:00-5:30) Every Friday Off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nadine G. Norton can be reached on (571) 272-1465. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Shamim Ahmed Primary Examiner Art Unit 1765

SA September 5, 2005